# **RD50-MPW3:**

# A fully monolithic digital CMOS sensor for future tracking detectors

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### Aims and Environment

#### **Goals RD50-CMOS**

- Study and develop radiation hard semiconductor tracking sensors
- Depleted Monolithic Active Pixel Sensor (DMAPS)
- Fabricated in commercial CMOS process for low cost and high availability

#### **RD50-MPW3: Possible applications**

- Radiation environment: >  $3 \cdot 10^{16} n_{eq}/cm^2$
- collider experiments beyond LHC, e.g. FCC
- Fast tracker for medical imaging

#### **Novelties RD50-MPW3**

- Very small pixel (thus: high granularity) with analog + digital electronics inside for signal pre-processing and configuration of single pixels
- Digital readout using a single 640 MHz differential line
- Capability for synchronizing internal timestamp with other detectors

	Key Facts
	<ul> <li>Fabrication</li> <li>LF15A process from LFoundry (150 nm)</li> <li>High-resistivity wafers: 1.9 kOhm·cm, 3 kOhm·cm (nominal)</li> <li>Submitted to foundry: Dec. 2021, received: Aug 2022</li> </ul>
	<ul> <li>Layout</li> <li>Matrix of 64 x 64 pixels, pixel size: 6 2um x 62 um</li> <li>Digital periphery next to matrix, total chip size: 5.1 mm x 6.6 mm</li> </ul>
	<ul> <li>Design</li> <li>FEI3-style pixel design based on predecessors RD50-MPW1 and RD50-MPW2</li> <li>Large collection electrode using deep N-well layer</li> <li>Analog-on-Top flow for chip level implementation</li> </ul>

#### Testing

#### Initial evaluation ongoing and successful so far

### **Pixel Matrix Design**

#### **Double-column architecture with FE-I3 readout**

- 64 pixel columns organized in 32 double columns
- To reduce crosstalk noise:
  - Digital signal lines are in the middle
  - Analog signals are on the side
  - Shielding lines between digital lines
- Share analog and digital lines within double column to save area
- Two metal layers form a power mesh to minimize voltage drop
- Readout follows the FE-I3 style (pixel on the top has the highest read priority)
- Each pixel can be configured through a shift-register chain inside each double column

#### Large fill factor DMAPS pixel

- Analog Front-End (AFE) and Digital Electronics (DE) are embedded in separate wells to minimise crosstalk noise
- Each pixel includes: -HV -HV • Pre-amplifier • High-pass filter • Discriminator • 4-bit trim-DAC Foundry 150 nr 8 8 • Readout logic • 8-bit configuration register • Capability to mask noisy pixels Pixel provides timestamps of leading and trailing edges of discriminator output, and pixel column address





## Advanced Test Structures

- **A) eTCT**: Mini 3x3 pixel matrix for timing and charge measurements using edge-TCT
- **B)** Capacitance: Single sensing diode for measuring capacitance of a single pixel
- **C)** + **D) TSC**: Two different layouts for Thermally Stimulated Current (TSC) measurements for defect characterization.



### **Digital Readout Design**

### Periphery: Peripheral electronics for readout and configuration

- I End of Column (EOC) per double column to readout and configure pixels
- Control Unit (CU) to push data from EOCs to readout bus: 32-bit data bus
- Transmission unit (TX Unit): Derandomization of EOC data, framing, encoding and serialization; read-out at 640 MHz
- Common timestamp generator (TS):



### EOC: Configuration and readout of one double column

- 16 registers (8-bit) for pixel configuration: MUXed into serial stream
- I register (8-bit) for EOC configuration Serial read-back
- A 24-bit wide FIFO for pixel data: Derandomization of all pixel data in one double column
  - Single 32-bit register for data readout: (fixed) EOC address attached to data Combinatorial token-handler for priority logic of EOC: Highest address readout first (rolling shutter)

fanned-out into all double columns I2C to wishbone controller: convert external I2C commands to internal wishbone commands

### **Designers and Acknowledgements**

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### **RD50-MPW3** papers

E. Vilella, Development of High Voltage-CMOS sensors within the CERN-RD50 collaboration (VERTEX2021)

P. Sieberer, et.al., Design and Characterization of Depleted Monolithic Active Pixel Sensors within the RD50 Collaboration (VCI2022)





